



2017 Excellent Student Award of The IEEE Fukuoka Section

is presented to

Yucong Zhang

for the paper, co-authored with Stefan Holst, Xiaoqing Wen, Kohei Miyase, Seiji Kajihara, Jun Qian, entitled “Scan Chain Grouping for Mitigating IR-Drop-Induced Test Data Corruption”, published in Proc. of The 26th IEEE Asian Test Symposium, pp. 145-150, November 2017.

February 2018

A handwritten signature in black ink, appearing to read 'Tanemasa Asano'.

Tanemasa Asano
Chair, IEEE Fukuoka Section

